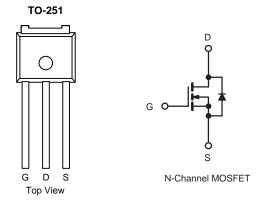


N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)		
30	0.007at V _{GS} = 10 V	40	13.8 nC		
	0.010 at V _{GS} = 4.5 V	40	13.0110		



FEATURES

- DT-Trench Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

- · Low-Side Switch
- Notebook DC/DC

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 20		
Continuous Drain Current (T _J = 150 °C) Pulsed Drain Current	$T_C = 25 \degree C$ $T_C = 70 \degree C$ $T_A = 25 \degree C$	I _D	40 ^a 40 ^a 22.7 ^{b, c}		
	T _A = 70 °C	I _{DM}	19.7 ^{b, c}	Α	
Avalanche Current	1 0411	I _{AS}	35		
Avalanche Energy L = 0.1 mH		E _{AS}	61	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C T _A = 25 °C	I _S	40 ^a 4.1 ^{b, c}		
Maximum Power Dissipation		P _D	50 32 5 ^{b, c} 3.2 ^{b, c}	W	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	
Soldering Recommendations (Peak Tempera		260			

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R_{thJA}	20	25	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	2.0	2.5	7	

- a. Based on T_C = 25 °C. Package limited.
 b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static			•	•	•	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, I}_{D} = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		27		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1		3	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
7 0 1 1/1 5 1 0 1	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μА	
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	50			Α	
Dunin Course On Chata Desistance		V _{GS} = 10 V, I _D = 20 A		0.007	0.008	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 18 \text{ A}$		0.010	0.011		
Forward Transconductance ^a	g _{fs}	V _{DS} = 15 V, I _D = 20 A		90		S	
Dynamic ^b							
Input Capacitance	C _{iss}			1720		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		355			
Reverse Transfer Capacitance	C _{rss}			130			
Total Oats Ohanna		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		29	44	nC	
Total Gate Charge				13.8	21		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 20 \text{ A}$		5.0			
Gate-Drain Charge	Q _{gd}			4.6			
Gate Resistance	R_g	f = 1 MHz		1.1	2.2	Ω	
Turn-On Delay Time	t _{d(on)}			25	40	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 15 Ω		14	25		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ 1.0 A, V_{GEN} = 4.5 V, R_g = 1 Ω		30	45		
Fall Time	t _f			15	25		
Turn-On Delay Time	t _{d(on)}			11	20		
Rise Time	t _r	V_{DD} = 15 V, R_L = 15 Ω		9	15		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 1.0 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		27	40		
Fall Time	t _f			9	15		
Drain-Source Body Diode Characteristi	cs			•			
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			40	۸	
Pulse Diode Forward Current	I _{SM}				120	_ A	
Body Diode Voltage	V_{SD}	I _S = 4.1 A, V _{GS} = 0 V		0.75	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			25	50	ns	
Body Diode Reverse Recovery Charge	Q_{rr}	I _F = 4.1 A, dI/dt = 100 A/μs, T _{.I} = 25 °C		17	35	nC	
Reverse Recovery Fall Time	t _a	$1 = 4.1 \text{ A}$, $1 = 100 \text{ A/} \mu \text{ s}$, $1 = 25 \text{ C}$		13			
Reverse Recovery Rise Time	t _b			12		ns	

Notes:

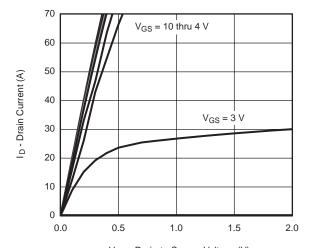
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$

b. Guaranteed by design, not subject to production testing.

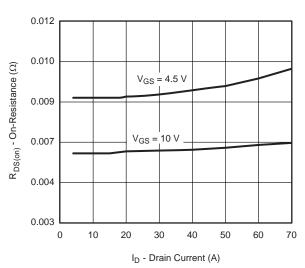


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

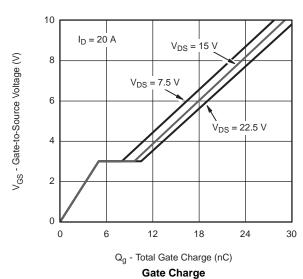


V_{DS} - Drain-to-Source Voltage (V)

Output Characteristics



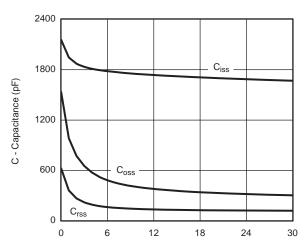
On-Resistance vs. Drain Current and Gate Voltage



1.2 1.0 ID - Drain Current (A) 0.8 T_C = 25 °C 0.6 0.4 T_C = 125 °C 0.2 55 °C 0.0 0.0 0.5 1.0 1.5 2.0 2.5 3.0

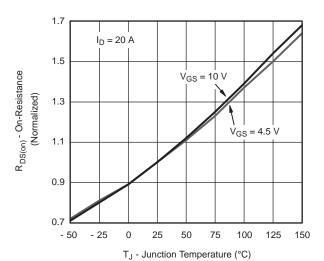
V_{GS} - Gate-to-Source Voltage (V)





 $V_{\mbox{\footnotesize{DS}}}$ - Drain-to-Source Voltage (V)

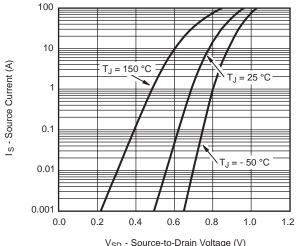
Capacitance

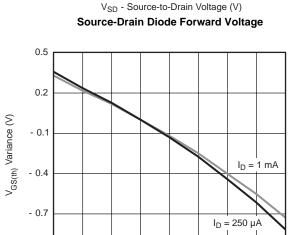


On-Resistance vs. Junction Temperature



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted





T_J - Temperature (°C)

Threshold Voltage

50

75

100

125

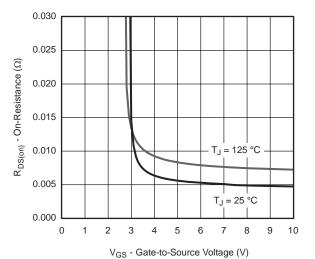
150

- 50

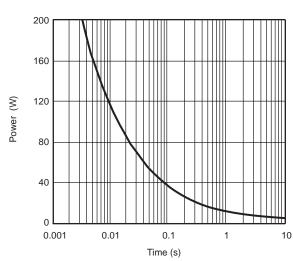
- 25

0

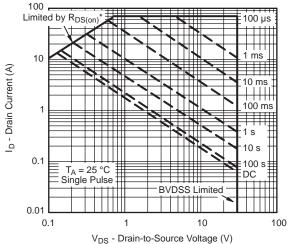
25



On-Resistance vs. Gate-to-Source Voltage



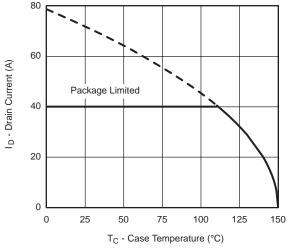
Single Pulse Power (Junction-to-Ambient)



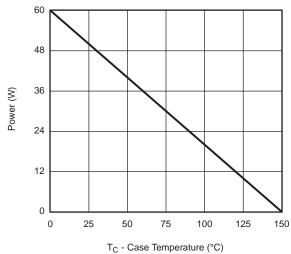
* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

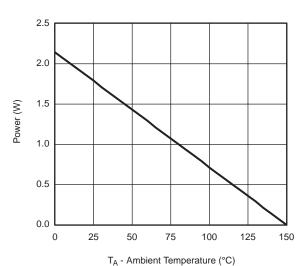
Safe Operating Area, Junction-to-Ambient

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Current Derating*



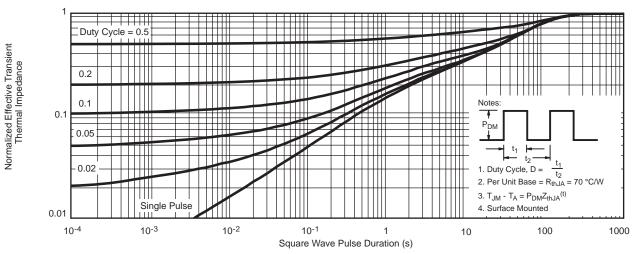


Power, Junction-to-Case Power, Junction-to-Ambient

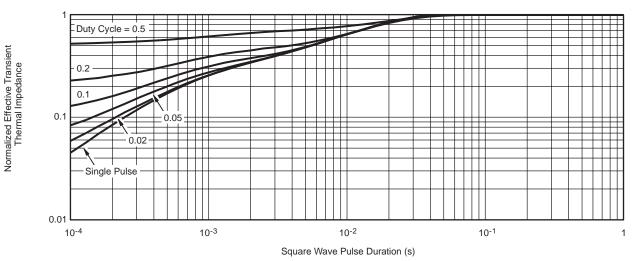
^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case





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